

N-channel 600 V, 0.175 Ω typ., 19.5 A, FDmesh™ II Power MOSFET (with fast diode) in PowerFLAT™ 8x8 HV package

Datasheet – production data

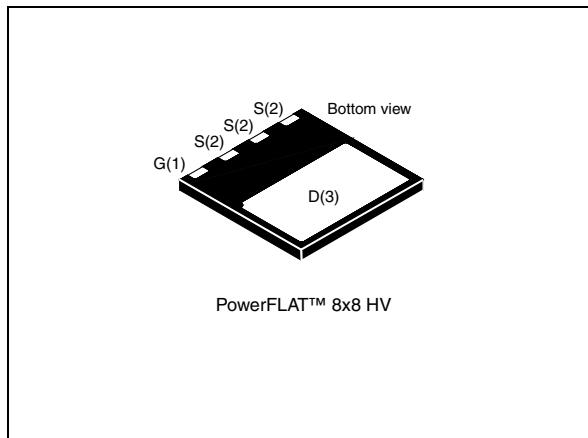
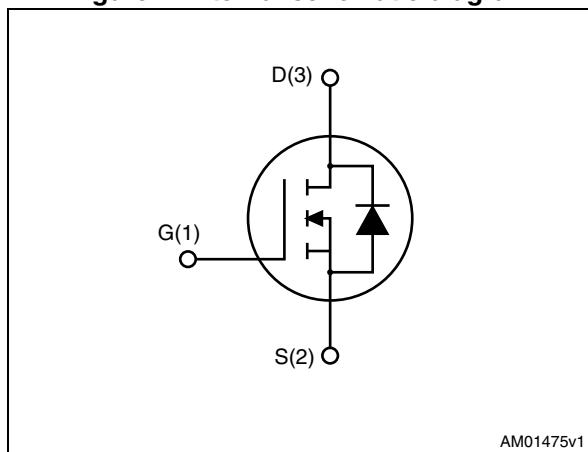


Figure 1. Internal schematic diagram



Features

Order code	V _{DS} @ T _{Jmax}	R _{DS(on)} max	I _D
STL23NM60ND	650 V	0.199 Ω	19.5 A ⁽¹⁾

1. This value is rated according to R_{thj-case}.

- Worldwide best R_{DS(on)} * area amongst the fast silicon based devices
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- High dv/dt and avalanche capabilities

Applications

- Switching applications

Description

This FDmesh™ II Power MOSFET with intrinsic fast-recovery body diode is produced using the second generation of MDmesh™ technology. Utilizing a new strip-layout vertical structure, this revolutionary device features extremely low on-resistance and superior switching performance. It is ideal for bridge topologies and ZVS phase-shift converters.

Table 1. Device summary

Order code	Marking	Package	Packaging
STL23NM60ND	23NM60ND	PowerFLAT™ 8x8 HV	Tape and reel

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 25	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	19.5	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	11.7	A
$I_{DM}^{(1),(2)}$	Drain current (pulsed)	78	A
$I_D^{(3)}$	Drain current (continuous) at $T_{amb} = 25^\circ\text{C}$	2.75	A
$I_D^{(3)}$	Drain current (continuous) at $T_{amb} = 100^\circ\text{C}$	1.75	A
$I_{DM}^{(2),(3)}$	Drain current (pulsed)	11	A
$P_{TOT}^{(3)}$	Total dissipation at $T_{amb} = 25^\circ\text{C}$	150	W
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25^\circ\text{C}$	3	W
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max)	9	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	700	mJ
$dv/dt^{(4)}$	Peak diode recovery voltage slope	40	V/ns
T_{stg}	Storage temperature	- 55 to 150	$^\circ\text{C}$
T_j	Max. operating junction temperature	150	$^\circ\text{C}$

1. The value is rated according to $R_{thj-case}$
2. Pulse width limited by safe operating area.
3. When mounted on FR-4 board of inch^2 , 2oz Cu.
4. $I_{SD} \leq 19.5\text{ A}$, $di/dt \leq 600\text{ A}/\mu\text{s}$, $V_{DD} = 80\% V_{(BR)DSS}$, $V_{DS(\text{peak})} < V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.83	$^\circ\text{C}/\text{W}$
$R_{thj-amb}^{(1)}$	Thermal resistance junction-ambient max	45	$^\circ\text{C}/\text{W}$

1. When mounted on FR-4 board of inch^2 , 2oz Cu.

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0$, $I_D = 1 \text{ mA}$	600			V
$dv/dt^{(1)}$	Drain-source voltage slope	$V_{DD} = 480 \text{ V}$, $I_D = 19.5 \text{ A}$, $V_{GS} = 10 \text{ V}$		30		V/ns
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0$, $V_{DS} = 600 \text{ V}$			1	μA
		$V_{GS} = 0$, $V_{DS} = 600 \text{ V}$, $T_C = 125^\circ\text{C}$			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0$, $V_{GS} = \pm 20 \text{ V}$			± 100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	3	4	5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$		0.175	0.199	Ω

1. Characteristic value at turn off on inductive load

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 50 \text{ V}$, $f = 1 \text{ MHz}$, $V_{GS} = 0$	-	2100	-	pF
C_{oss}	Output capacitance		-	80	-	pF
C_{rss}	Reverse transfer capacitance		-	10	-	pF
$C_{oss \text{ eq}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0$, $V_{DS} = 0 \text{ to } 480 \text{ V}$	-	310	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}$ gate DC Bias=0 test signal level=20 mV	-	4	-	Ω
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}$, $I_D = 19.5 \text{ A}$, $V_{GS} = 10 \text{ V}$ (see Figure 14)	-	69	-	nC
Q_{gs}	Gate-source charge		-	13	-	nC
Q_{gd}	Gate-drain charge		-	35	-	nC

1. $C_{oss \text{ eq}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$, $I_D = 10 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see <i>Figure 13</i>)	-	21	-	ns
t_r	Voltage rise time		-	19	-	ns
$t_{d(off)}$	Turn-off delay time		-	92	-	ns
t_f	Current fall time		-	42	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		19.5	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		78	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 19.5 \text{ A}$, $V_{GS} = 0$	-		1.3	V
t_{rr}	Reverse recovery time	$I_{SD} = 19.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <i>Figure 15</i>)	-	190		ns
Q_{rr}	Reverse recovery charge		-	1.2		nC
I_{RRM}	Reverse recovery current		-	13		A
t_{rr}	Reverse recovery time		-	270		ns
Q_{rr}	Reverse recovery charge	$I_{SD} = 21.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$, $T_j = 150^\circ\text{C}$ (see <i>Figure 15</i>)	-	2.0		nC
I_{RRM}	Reverse recovery current		-	15		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

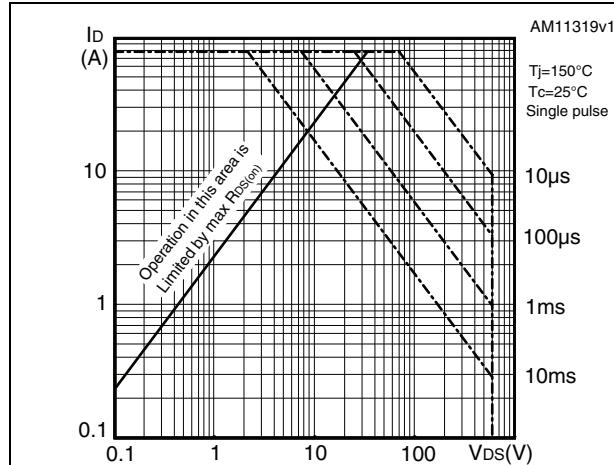


Figure 3. Thermal impedance

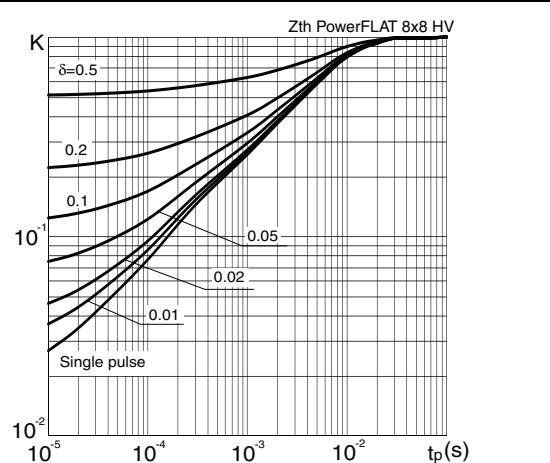


Figure 4. Output characteristics

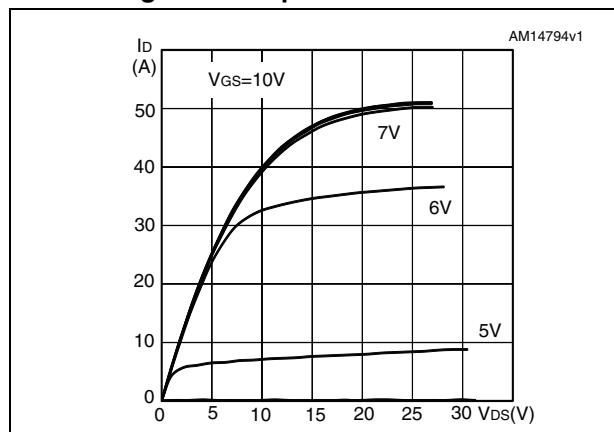


Figure 5. Transfer characteristics

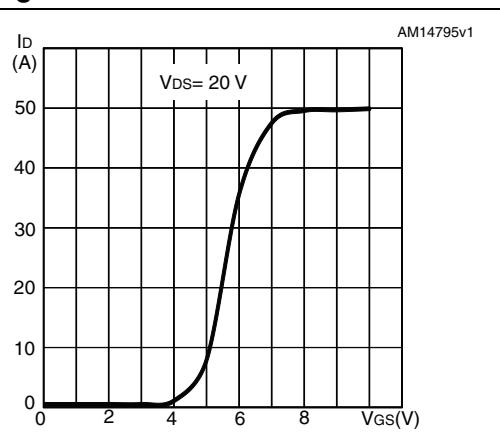
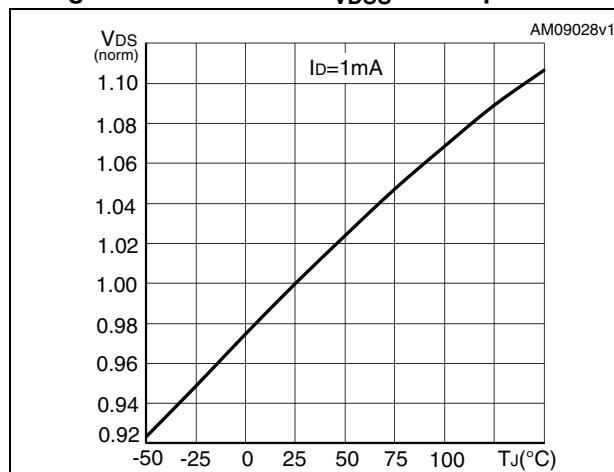
Figure 6. Normalized B_{VDSS} vs temperature

Figure 7. Static drain-source on-resistance

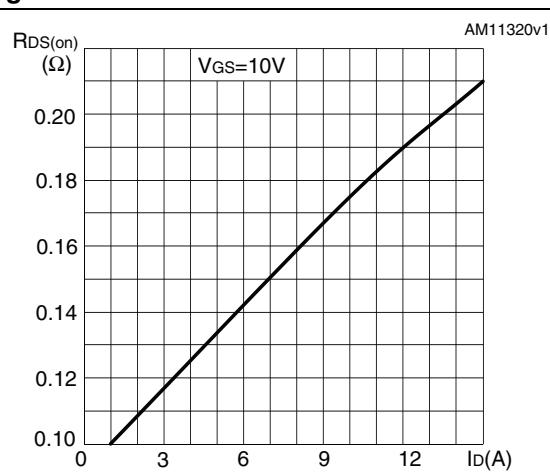
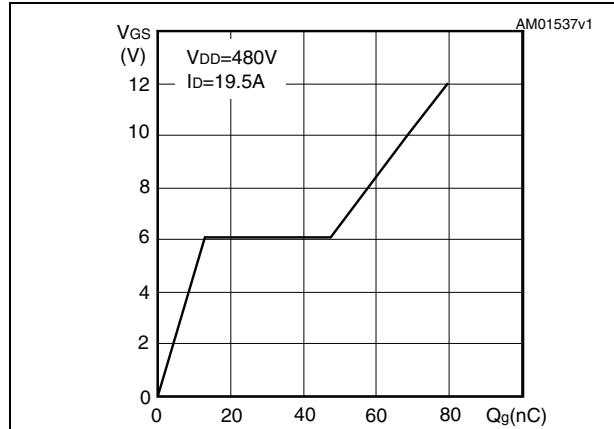
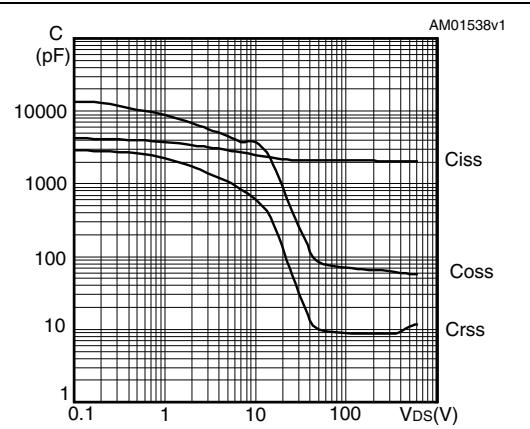
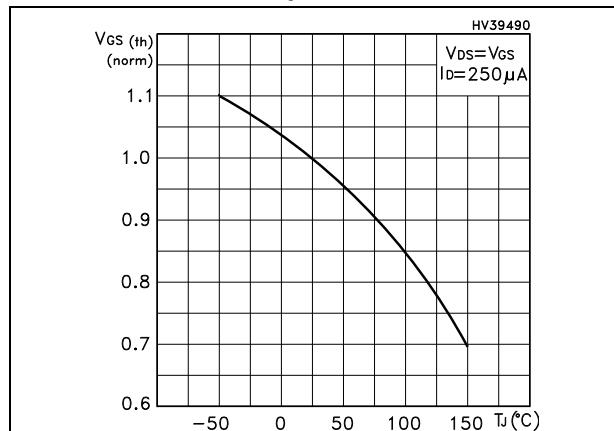
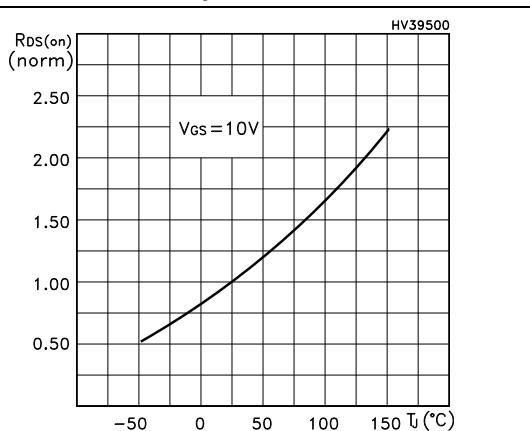
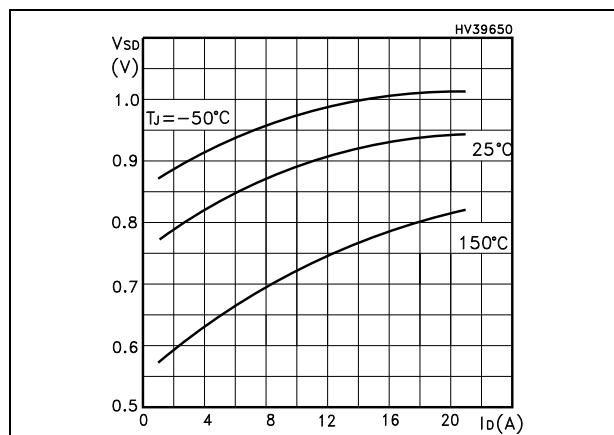


Figure 8. Gate charge vs gate-source voltage**Figure 9. Capacitance variations****Figure 10. Normalized gate threshold voltage vs temperature****Figure 11. Normalized on-resistance vs temperature****Figure 12. Source-drain diode forward characteristics**

3 Test circuits

Figure 13. Switching times test circuit for resistive load

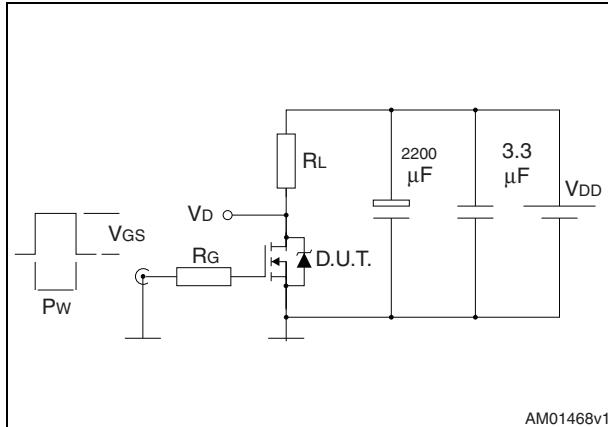


Figure 14. Gate charge test circuit

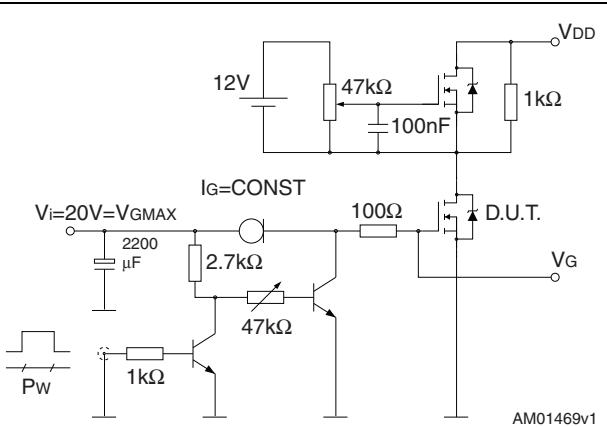


Figure 15. Test circuit for inductive load switching and diode recovery times

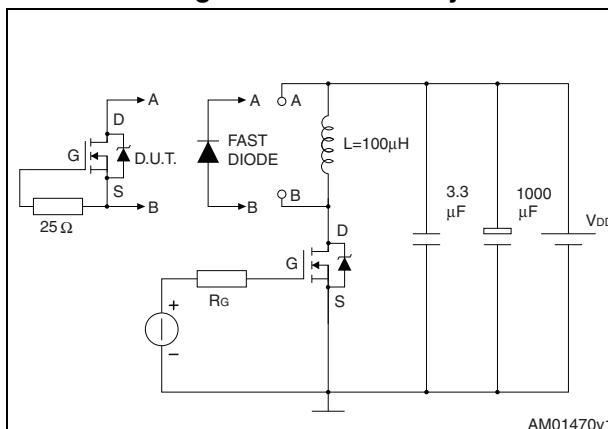


Figure 16. Unclamped inductive load test circuit

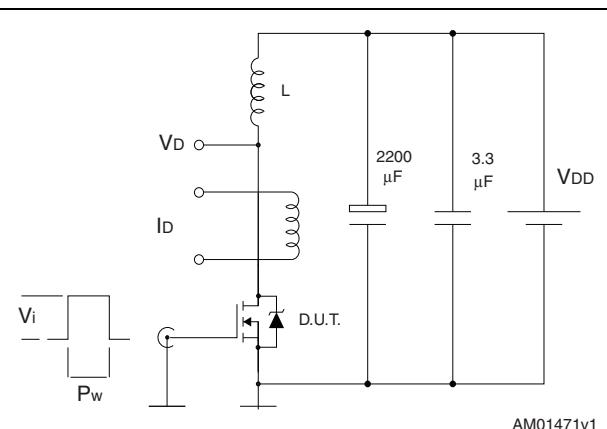


Figure 17. Unclamped inductive waveform

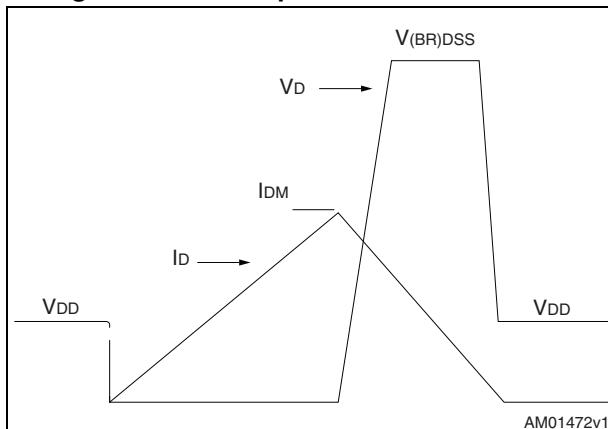
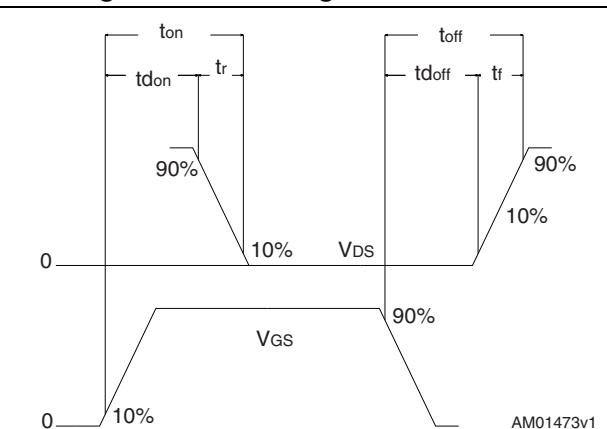


Figure 18. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

Table 8. PowerFLAT™ 8x8 HV mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
e		2.00	
L	0.40	0.50	0.60
aaa		0.10	
bbb		0.10	
ccc		0.10	

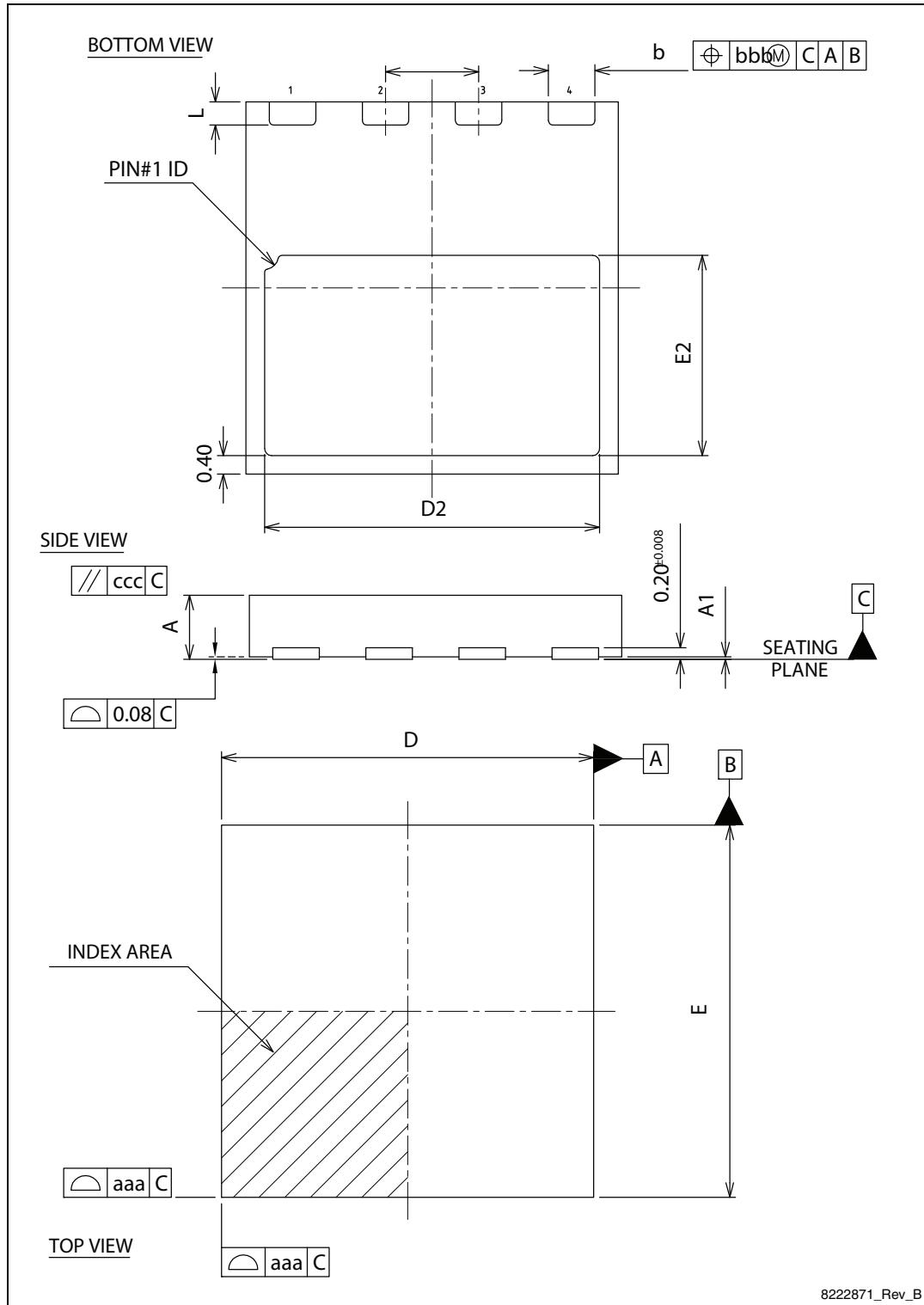
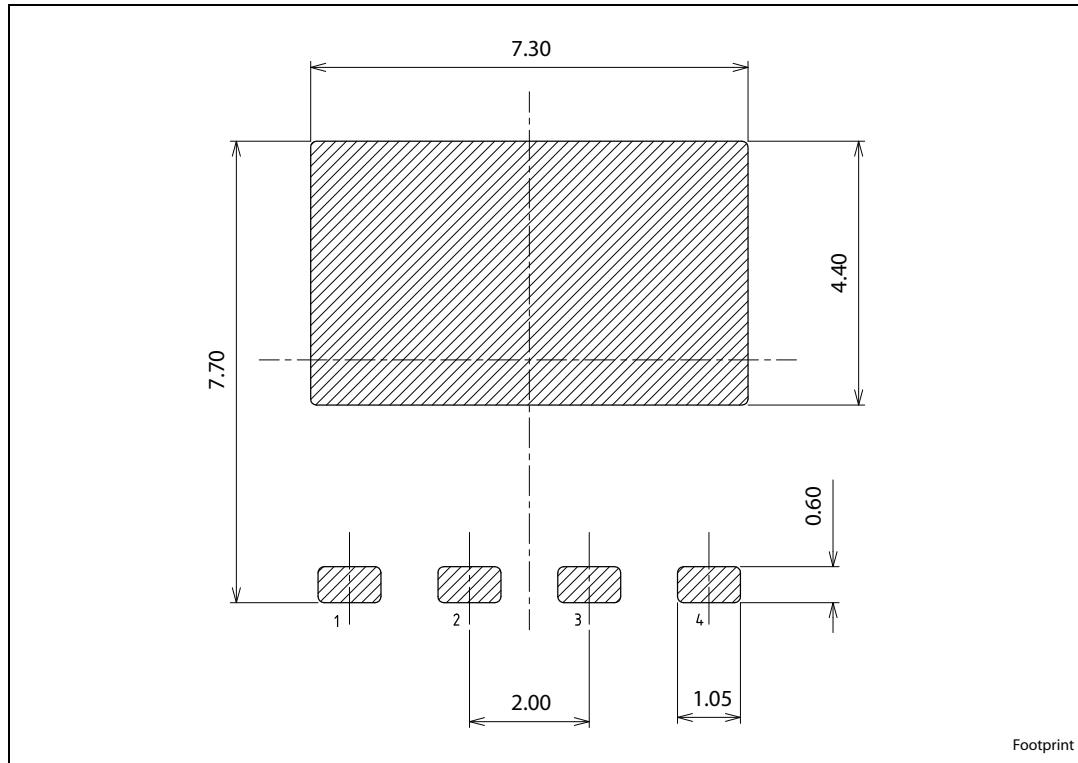
Figure 19. PowerFLAT™ 8x8 HV drawing mechanical data

Figure 20. PowerFLAT™ 8x8 HV recommended footprint

5 Packaging mechanical data

Figure 21. PowerFLAT™ 8x8 HV tape

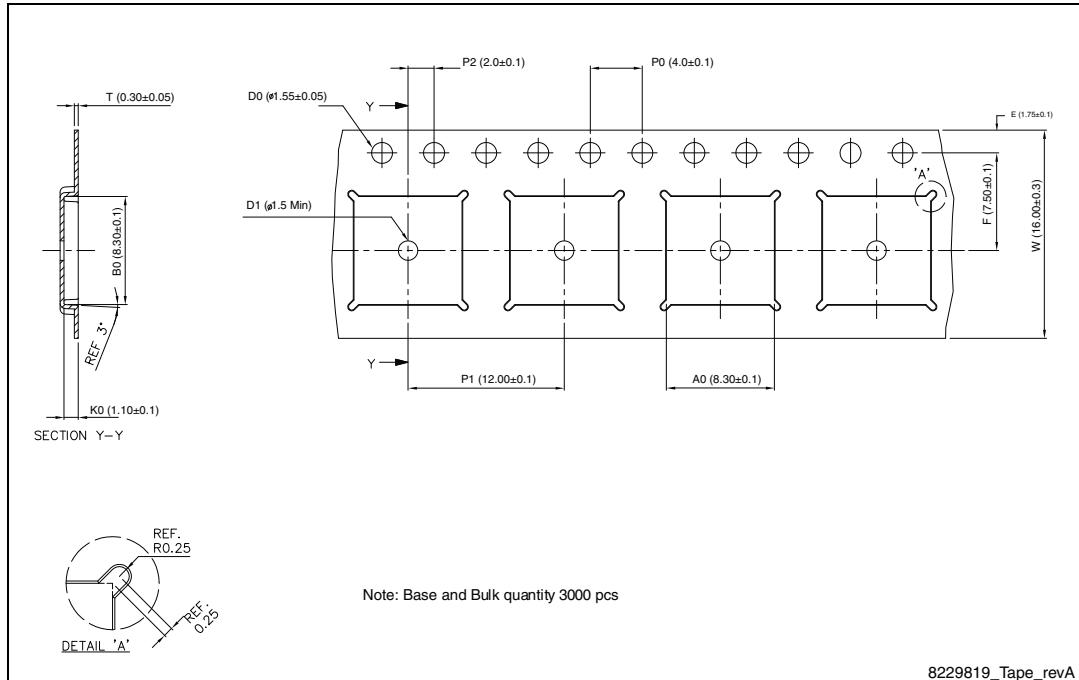


Figure 22. PowerFLAT™ 8x8 HV package orientation in carrier tape.

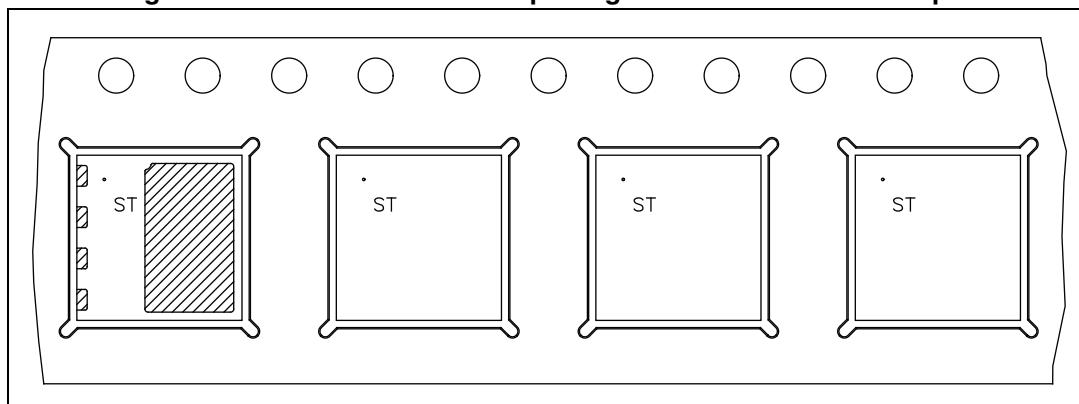
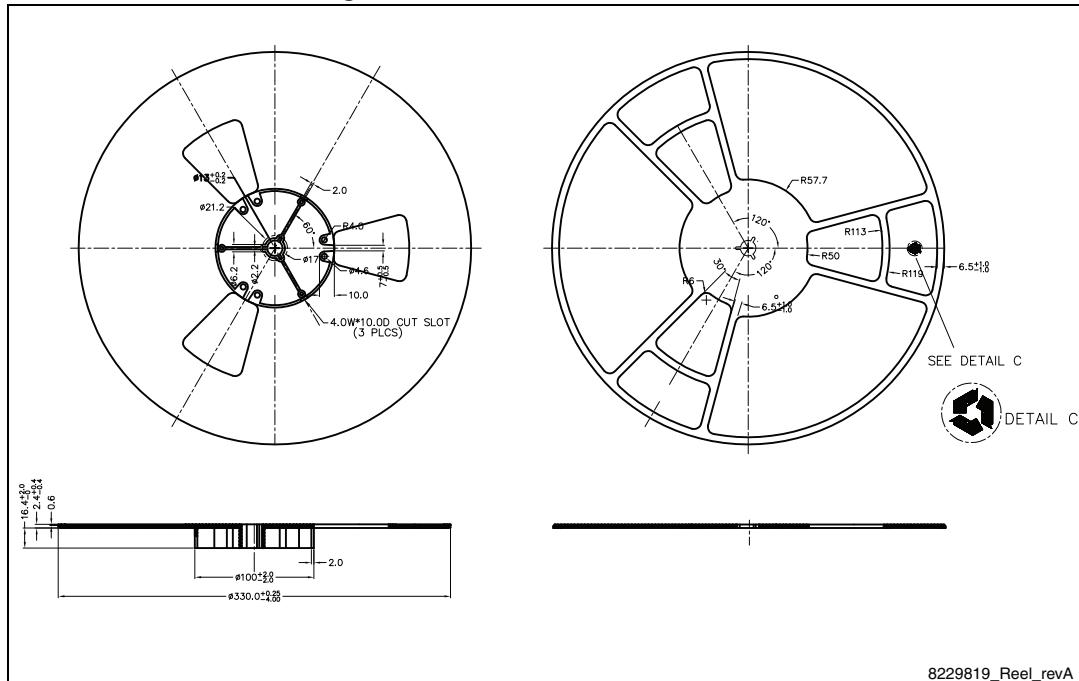


Figure 23. PowerFLAT™ 8x8 HV reel



6 Revision history

Table 9. Document revision history

Date	Revision	Changes
28-Apr-2010	1	First release.
01-Mar-2013	2	<ul style="list-style-type: none">– <i>Section 4: Package mechanical data</i> has been modified.– <i>Section 2.1: Electrical characteristics (curves)</i> has been inserted.– Minor text changes.

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